

MOS FIELD EFFECT TRANSISTOR

NP84N055EHE, NP84N055KHE

NP84N055CHE, NP84N055DHE, NP84N055MHE, NP84N055NHE

SWITCHING N-CHANNEL POWER MOS FET

DESCRIPTION

These products are N-channel MOS Field Effect Transistors designed for high current switching applications.

ORDERING INFORMATION

PART NUMBER	LEAD PLATING	PACKING	PACKAGE	
NP84N055EHE-E1-AY Note1, 2			TO-263 (MP-25ZJ) typ. 1.4 g	
NP84N055EHE-E2-AY Note1, 2	Duro Sp. (Tip)	Tana 900 n/raal		
NP84N055KHE-E1-AY Note1	Pure Sn (Tin)	Tape 800 p/reel	TO 202 (MD 257K) to 4.5 c	
NP84N055KHE-E2-AY Note1			TO-263 (MP-25ZK) typ. 1.5 g	
NP84N055CHE-S12-AZ Note1, 2	Sn-Ag-Cu		TO-220 (MP-25) typ. 1.9 g	
NP84N055DHE-S12-AY Note1, 2		Tubo FO s/tubo	TO-262 (MP-25 Fin Cut) typ. 1.8 g	
NP84N055MHE-S18-AY Note1	Pure Sn (Tin)	Tube 50 p/tube	TO-220 (MP-25K) typ. 1.9 g	
NP84N055NHE-S18-AY Note1			TO-262 (MP-25SK) typ. 1.8 g	

Notes 1. Pb-free (This product does not contain Pb in the external electrode.)

2. Not for new design

FEATURES

- Channel temperature 175 degree rated
- Super low on-state resistance

 $R_{DS(on)} = 7.3 \text{ m}\Omega$ MAX. (Vgs = 10 V, ID = 42 A)

• Low input capacitance

Ciss = 4540 pF TYP.

• Built-in gate protection diode

(TO-220)



(TO-262)





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ABSOLUTE MAXIMUM RATINGS (TA = 25°C)

Drain to Source Voltage (Vgs = 0 V)	Voss	55	V
Gate to Source Voltage (VDS = 0 V)	Vgss	±20	V
Drain Current (DC) (Tc = 25°C) Note1	ID(DC)	±84	Α
Drain Current (pulse) Note2	ID(pulse)	±336	Α
Total Power Dissipation (T _A = 25°C)	Рт	1.8	W
Total Power Dissipation (Tc = 25°C)	Рт	200	W
Channel Temperature	Tch	175	°C
Storage Temperature	Tstg	-55 to +175	°C
Single Avalanche Current Note3	las	84/56/21	Α
Single Avalanche Energy Note3	Eas	70/313/441	mJ

Notes 1. Calculated constant current according to MAX. allowable channel temperature.

- **2.** PW \leq 10 μ s, Duty cycle \leq 1%
- 3. Starting T_{ch} = 25°C, V_{DD} = 28 V, R_G = 25 Ω , V_{GS} = 20 \rightarrow 0 V (See Figure 4.)

THERMAL RESISTANCE

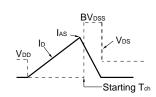
Channel to Case Thermal Resistance	Rth(ch-C)	0.75	°C/W
Channel to Ambient Thermal Resistance	Rth(ch-A)	83.3	°C/W

ELECTRICAL CHARACTERISTICS (TA = 25°C)

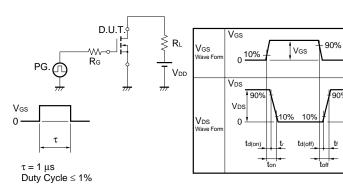
CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	IDSS	V _{DS} = 55 V, V _{GS} = 0 V			10	μA
Gate Leakage Current	Igss	V _{GS} = ±20 V, V _{DS} = 0 V			±10	μΑ
Gate to Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	2.0	3	4.0	V
Forward Transfer Admittance	yfs	V _{DS} = 10 V, I _D = 42 A	20	44		S
Drain to Source On-state Resistance	R _{DS(on)}	V _{GS} = 10 V, I _D = 42 A		5.8	7.3	mΩ
Input Capacitance	Ciss	V _{DS} = 25 V,		4540	6810	pF
Output Capacitance	Coss	V _{GS} = 0 V,		710	1070	pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		340	620	pF
Turn-on Delay Time	t _{d(on)}	V _{DD} = 28 V, I _D = 42 A,		37	81	ns
Rise Time	tr	V _{GS} = 10 V,		22	54	ns
Turn-off Delay Time	t _{d(off)}	R _G = 1 Ω		76	150	ns
Fall Time	tr			22	56	ns
Total Gate Charge	Q _G	V _{DD} = 44 V,		88	130	nC
Gate to Source Charge	Qgs	V _{GS} = 10 V,		22		nC
Gate to Drain Charge	Q _{GD}	I _D = 84 A		31		nC
Body Diode Forward Voltage	V _{F(S-D)}	I _F = 84 A, V _{GS} = 0 V		1.0		V
Reverse Recovery Time	trr	I _F = 84 A, V _{GS} = 0 V,		49		ns
Reverse Recovery Charge	Qrr	di/dt = 100 A/μs		78		nC

TEST CIRCUIT 1 AVALANCHE CAPABILITY

$\begin{array}{c} \text{D.U.T.} \\ \text{Rg} = 25 \, \Omega \\ \text{Ves} = 20 \rightarrow 0 \, \text{V} \\ \end{array} \begin{array}{c} \text{PG.} \\ \text{W} \\ \text{W} \end{array} \begin{array}{c} \text{S} \\ \text{S} \\ \text{M} \end{array} \begin{array}{c} \text{I} \\ \text{M} \\ \text{M} \end{array} \begin{array}{c} \text{Volume} \\ \text{M} \end{array}$



TEST CIRCUIT 2 SWITCHING TIME



TEST CIRCUIT 3 GATE CHARGE

$$\begin{array}{c|c} D.U.T. \\ I_G = 2 \underset{\longrightarrow}{mA} \\ \downarrow \vdots \\ \downarrow \downarrow \\ PG. \\ \begin{array}{c} \searrow \\ \searrow \\ \searrow \\ \end{array} \begin{array}{c} R_L \\ \\ \searrow \\ \searrow \\ \end{array} \begin{array}{c} V_{DD} \\ \\ \searrow \\ \end{array}$$

TYPICAL CHARACTERISTICS (TA = 25°C)

Figure 1. DERATING FACTOR OF FORWARD BIAS SAFE OPERATING AREA

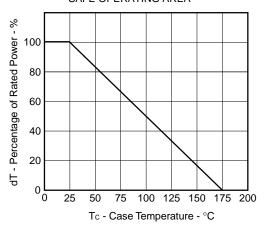


Figure 3. FORWARD BIAS SAFE OPERATING AREA

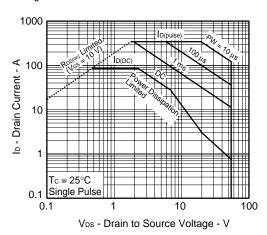


Figure2. TOTAL POWER DISSIPATION vs. CASE TEMPERATURE

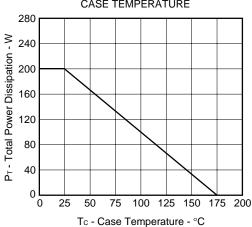


Figure 4. SINGLE AVALANCHE ENERGY DERATING FACTOR

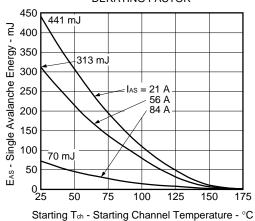


Figure 5. TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH

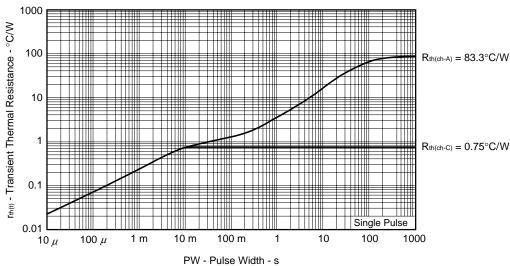


Figure 6. FORWARD TRANSFER CHARACTERISTICS

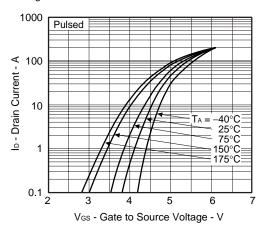


Figure7. DRAIN CURRENT vs.
DRAIN TO SOURCE VOLTAGE 400 Pulsed 320 lo - Drain Current - A Vgs = 10 V 240 160 80 0 2 3

Figure8. FORWARD TRANSFER ADMITTANCE vs. DRAIN CURRENT

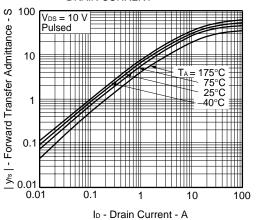


Figure9. DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE

V_{DS} - Drain to Source Voltage - V

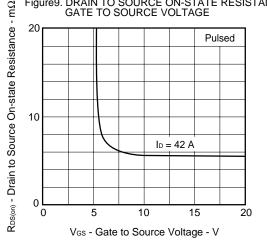
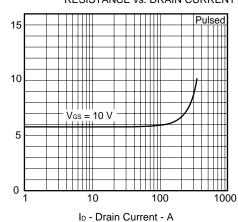


Figure 10. DRAIN TO SOURCE ON-STATE RESISTANCE vs. DRAIN CURRENT



R_{DS(on)} - Drain to Source On-state Resistance - mΩ

Figure 11. GATE TO SOURCE THRESHOLD VOLTAGE vs. CHANNEL TEMPERATURE

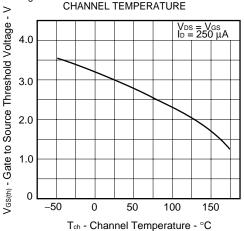
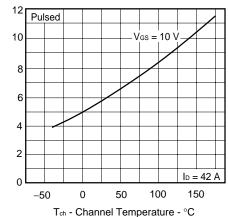


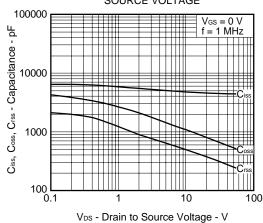
Figure 12. DRAIN TO SOURCE ON-STATE RESISTANCE vs. CHANNEL TEMPERATURE



RDS(on) - Drain to Source On-state Resistance - mΩ

Figure 13. SOURCE TO DRAIN DIODE FORWARD VOLTAGE 1000 Pulsed IF - Diode Forward Current - A = 10 V100 0 \ 10 0.1 0 1.5 1.0 0.5 $V_{F(S-D)}$ - Source to Drain Voltage - V

Figure 14. CAPACITANCE vs. DRAIN TO SOURCE VOLTAGE



1000

Figure 15. SWITCHING CHARACTERISTICS

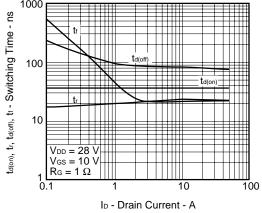


Figure 16. REVERSE RECOVERY TIME vs. DIODE FORWARD CURRENT

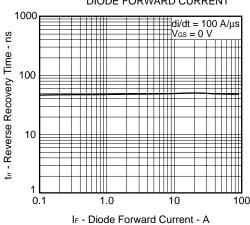
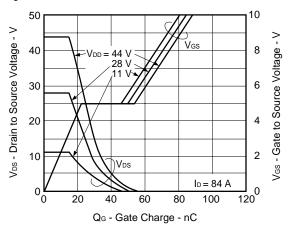
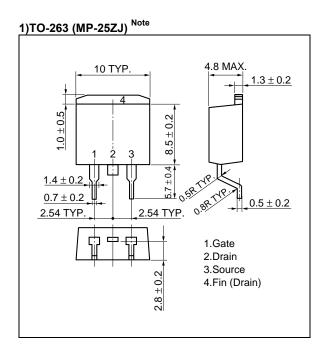
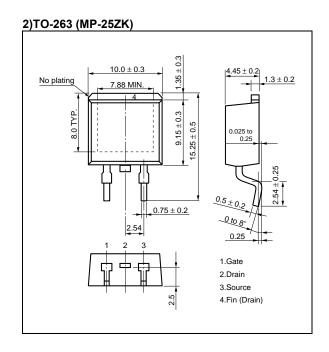


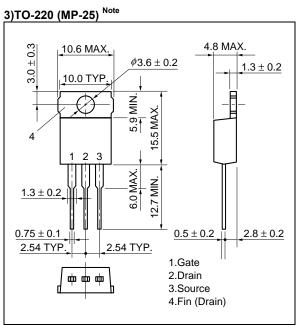
Figure 17. DYNAMIC INPUT/OUTPUT CHARACTERISTICS

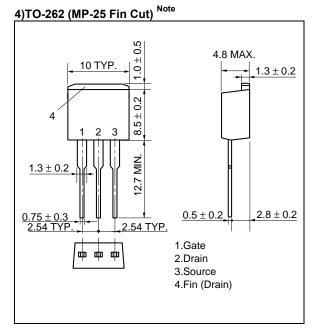


<R> PACKAGE DRAWINGS (Unit: mm)

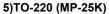


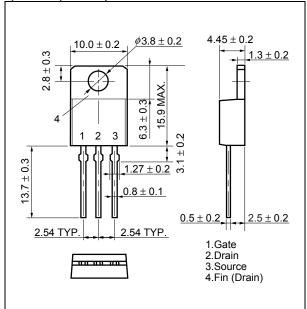


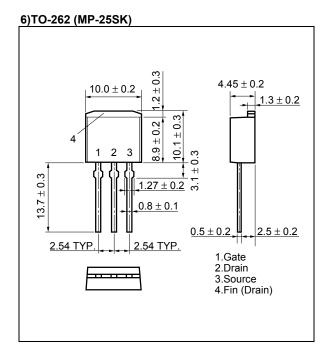




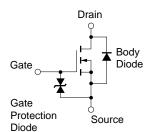
Note Not for new design







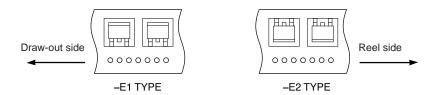
EQUIVALENT CIRCUIT



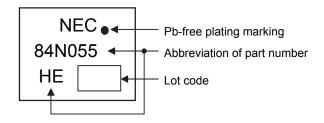
Remark The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

<R> TAPE INFORMATION

There are two types (-E1, -E2) of taping depending on the direction of the device.



<R> MARKING INFORMATION



<R> RECOMMENDED SOLDERING CONDITIONS

These products should be soldered and mounted under the following recommended conditions.

For soldering methods and conditions other than those recommended below, please contact an NEC Electronics sales representative.

For technical information, see the following website.

Semiconductor Device Mount Manual (http://www.necel.com/pkg/en/mount/index.html)

Soldering Method	Soldering Conditions	Recommended Condition Symbol	
Infrared reflow	Maximum temperature (Package's surface temperature): 260°C or below		
MP-25ZJ, MP-25ZK	Time at maximum temperature: 10 seconds or less		
	Time of temperature higher than 220°C: 60 seconds or less	ID00 00 0	
	Preheating time at 160 to 180°C: 60 to 120 seconds	IR60-00-3	
	Maximum number of reflow processes: 3 times		
	Maximum chlorine content of rosin flux (percentage mass): 0.2% or less		
Wave soldering	Maximum temperature (Solder temperature): 260°C or below		
MP-25, MP-25K, MP-25SK,	Time: 10 seconds or less	THDWS	
MP-25 Fin Cut	Maximum chlorine content of rosin flux: 0.2% (wt.) or less		
Partial heating	Maximum temperature (Pin temperature): 350°C or below		
MP-25ZJ, MP-25ZK,	Time (per side of the device): 3 seconds or less	P350	
MP-25K, MP-25SK	Maximum chlorine content of rosin flux: 0.2% (wt.) or less		
Partial heating	Maximum temperature (Pin temperature): 300°C or below		
MP-25, MP-25 Fin Cut	Time (per side of the device): 3 seconds or less	P300	
	Maximum chlorine content of rosin flux: 0.2% (wt.) or less		

Caution Do not use different soldering methods together (except for partial heating).

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